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Key indicators

Single-crystal X-ray study T = 153 K Mean σ (Zr–Te) = 0.005 Å R factor = 0.025 wR factor = 0.067 Data-to-parameter ratio = 28.6

For details of how these key indicators were automatically derived from the article, see http://journals.iucr.org/e.

Caesium zirconium uranium pentatelluride, CsZrUTe₅

CsZrUTe₅ is isostructural with CsTiUTe₅. In the asymmetric unit, the site symmetries of the Cs, U, Zr, Te1, Te2 and Te3 atoms are *mm2*, *mm2*, *.2/m.*, *m..*, *.2*. and *mm2*, respectively. CsZrUTe₅ has a layered structure that contains UTe₈ bicapped trigonal prisms sharing a common edge with ZrTe₆ octahedra. Cs cations separate the layers. The structure contains an infinite linear Te–Te chain, with Te atoms separated by 3.1551 (4) Å.

Comment

The structure of the compound CsTiUTe₅ (Cody & Ibers, 1995) features an infinite linear chain of short Te–Te interactions, the Te–Te distance being 3.065 (1) Å. Despite the presence of this chain, the compound is a semiconductor. Crystals sufficiently large to allow more complete conductivity measurements could not be grown. Accordingly, we turned our attention to the synthesis of the possible Zr analogue, namely CsZrUTe₅. The compound has been synthesized and its structure is reported here. Unfortunately, large crystals of this material have not been grown.



Figure 1

The structure of CsZrUTe₅, viewed approximately along [010]. The Te-Te bonds in the infinite chain are drawn as red lines. Displacement ellipsoids are displayed at the 99% probability level.

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Fig. 1 shows the crystal structure of CsZrUTe₅, which is isostructural with CsTiUTe₅ (Cody & Ibers, 1995). The anionic layers comprise UTe₈ bicapped trigonal prisms and ZrTe₆ octahedra. These layers are separated by Cs cations which are coordinated in a bicapped pentagonal prism of Te atoms.

The U-Te distances and U-atom coordination environment are similar to those found in UTe₂ (Beck & Dausch, 1988). In both structures, the UTe₈ bicapped trigonal prisms have a short Te-Te distance at one edge of the triangular face. In CsZrUTe₅ the prisms share edges of a rectangular face through Te2 atoms in the [100] direction. This results in an infinite linear chain of Te atoms; the Te-Te distance is 3.1551 (4) Å.

Each nearly regular $ZrTe_6$ octahedron shares faces with two adjacent octahedra to create an unusual infinite $[ZrTe_3^{2-}]$ chain. The Zr–Te distances (Table 1) are comparable with those of 2.8771 (7)–3.0426 (8) Å in ZrTe (Örlygsson & Harbrecht, 2001).

Experimental

CsZrUTe₅ was obtained as black needles from the reaction of Cs₂Te₃ (0.11 mmol), U (Oak Ridge National Laboratory, 0.23 mmol), Zr (Chemtall GmbH, 0.23 mmol) and Te (Aldrich, 99.8%, 0.80 mmol) with CsCl (Strem, 99.999%) as flux. The Cs₂Te₃ reactive flux was prepared by the stoichiometric reaction of Cs (Alfa Aesar, 99.8%) and Te in liquid NH₃ at 194 K. The reactants were loaded into a fused-silica tube under an Ar atmosphere in a dry box. The tube was evacuated to 10^{-4} Torr (1 Torr = 133.322 Pa), sealed and placed in a computer-controlled furnace. The sample was heated to 1223 K, kept at 1223 K for 144 h and then slowly cooled at 2 K h⁻¹ to 293 K. The resulting crystals were extracted manually from the melt.

Crystal data

CsZrUTe ₅	Z = 2
$M_r = 1100.16$	$D_x = 6.675 \text{ Mg m}^{-3}$
Orthorhombic, Pmma	Mo $K\alpha$ radiation
a = 6.3101 (8) Å	$\mu = 31.99 \text{ mm}^{-1}$
b = 8.2299 (10) Å	T = 153 (2) K
c = 10.5401 (13) Å	Needle, black
$V = 547.36 (12) \text{ Å}^3$	0.336 \times 0.062 \times 0.056 mm
Data collection	

Bruker SMART 1000 CCD areadetector diffractometer ω scans Absorption correction: numerical face indexed (SHEL YTL)

face-indexed (SHELXTL; Sheldrick, 2003) $T_{min} = 0.039, T_{max} = 0.217$ 6537 measured reflections 801 independent reflections 769 reflections with $I > 2\sigma(I)$ $R_{\text{int}} = 0.038$ $\theta_{\text{max}} = 28.9^{\circ}$ Refinement

Refinement on F^2	$w = 1/[\sigma^2(F_o^2) + (0.04P)^2]$
$R[F^2 > 2\sigma(F^2)] = 0.025$	where $P = (F_0^2 + 2F_c^2)/3$
$wR(F^2) = 0.067$	$(\Delta/\sigma)_{\rm max} < 0.001$
S = 1.27	$\Delta \rho_{\rm max} = 3.85 \text{ e } \text{\AA}^{-3}$
801 reflections	$\Delta \rho_{\rm min} = -2.55 \text{ e } \text{\AA}^{-3}$
28 parameters	

Table 1		
Selected	bond lengths	(Å).

U1-Te1	3.0961 (6)	Te2-Te2 ⁱⁱ	3.1551 (4)
U1-Te2 U1-Te3 ⁱ	3.1118 (4)	Cs1-Te1 ⁱⁱⁱ	3.8725 (5)
	3.3599 (4)	Cs1-Te2	3.9828 (6)
Zr1-Te3 ⁱ	2.8890 (6)	Cs1-Te1 ^{iv}	4.0608 (8)
Zr1-Te1	2.9087 (4)	Cs1-Te3	4.1193 (5)

Symmetry codes: (i) -x, -y, -z + 1; (ii) $x + \frac{1}{2}$, y, -z + 1; (iii) -x, -y + 1, -z + 1; (iv) x, y, z + 1.

The structure was standardized by means of the program *STRUCTURE TIDY* (Gelato & Parthé, 1987). The highest peak is 0.03 Å and the deepest hole is 1.82 Å from atom U.

Data collection: *SMART* (Bruker, 2003); cell refinement: *SMART*; data reduction: *SAINT-Plus* (Bruker, 2003); program(s) used to solve structure: *SHELXTL* (Sheldrick, 2003); program(s) used to refine structure: *SHELXTL*; molecular graphics: *CRYSTALMAKER* (*CRYSTALMAKER* Software, 2005); software used to prepare material for publication: *SHELXTL*.

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